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Inventor Information for 10/536878

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US 4719551 A	19880112	Optically controlled power converting apparatus	363/41	257/114; 257/124; 257/136; 323/207; 327/467; 327/564; 363/128; 363/129; 363/136; 363/137;	Nishizawa; Junichi et al.

				363/37	
US 4719499	19880112	Semiconductor imaging	257/258	257/291;	Nishizawa;
A		device		257/749;	Junichi et al.
				257/E27.148;	
				348/307	
US 4712122	19871208	Heterojunction gate ballistic	257/27	257/192;	Nishizawa;
Α		JFET with channel thinner		257/264;	Junichi et al.
		than Debye length		257/266;	
				257/272;	
				257/E27.012;	
				257/E29.049;	
				257/E29.091;	
				257/E29.14;	:
				257/E29.243;	
				438/191;	
				438/193	
US 4700213	19871013	Multi-drain enhancement	257/262	257/264;	Nishizawa;
Α		JFET logic (SITL) with		257/E27.032;	Jun-ichi et al.
		complementary MOSFET		257/E27.059;	
		load		257/E29.194	
US 4692789	19870908	Semiconductor apparatus	257/664	257/136;	Nakamura;
A				257/688;	Yoshio et al.
				257/689;	
				257/724;	
				257/E21.506	
US 4692194	19870908	Method of performing	117/56	117/61;	Nishizawa;
Α		solution growth of a GaAs		117/67;	Jun-ichi
		compound semiconductor		117/907;	
		crystal layer under control		117/954;	
		of conductivity type thereof		257/E21.117;	
				438/915	
US 4686555	19870811	Solid state image sensor	257/446	257/113;	Yusa; Atsushi
A				257/258;	et al.
				257/291;	
				257/E27.148;	
				257/E29.243;	
				257/E31.079;	
			400/501	257/E31.085) T: 1 '
US 4685979	19870811	Method of manufacturing a	438/501	117/56;	Nishizawa;
A		group II-VI compound		117/67;	Jun-ichi
		semiconductor device		257/E21.464;	
		having a pn junction		257/E21.465;	
				257/E21.467;	
				257/E33.019;	
			0.55/2.55	438/22	01.45
US 4684968	19870804	JFET imager having light	257/258	257/291;	Ohta;

A		sensing inversion layer		257/446;	Yoshinori et
7.		induced by insulator charge		257/E27.148	al.
US 4684966	19870804	Static induction transistor	257/258	257/264;	Nishizawa;
A		photodetector having a deep		257/E27.131;	Junichi et al.
• •		shielding gate region		257/E27.148;	
				257/E29.059	
US 4673985	19870616	Semiconductor image sensor	348/307	257/258;	Nishizawa;
A				257/261;	Jun-ichi
				257/264;	
				257/296;	
				257/E27.148	
US 4673961	19870616	Pressurized contact type	257/181	257/136;	Nishizawa;
A	130,000	double gate static induction	i	257/727;	Jun-ichi et al.
**		thyristor		257/E23.078;	
				257/E23.187;	
				257/E29.196	
US 4668306	19870526	Method of manufacturing a	438/379	257/480;	Nishizawa;
A	150,0520	semiconductor device		257/E21.152;	Jun-ichi
**		having unhomogeneous		257/E21.341;	
		distribution of impurity		257/E21.473;	
		concentration		257/E29.109;	
		Concontraction		257/E29.338;	
				438/508;	
				438/522	
US 4660062	19870421	Insulated gate transistor	257/345	257/384;	Nishizawa;
A		having reduced channel		257/E21.426;	Junichi et al.
**		length		257/E21.429;	
		10-15-1-		257/E21.43;	
				257/E29.13;	
				257/E29.131;	
				257/E29.154;	
				257/E29.156;	
				257/E29.16;	
				257/E29.243;	
				257/E29.26	
US 4651180	19870317	Semiconductor photoelectric	257/257	257/261;	Nishizawa;
A		transducer		257/264;	Jun-ichi et al.
**				257/270;	
				257/E27.148;	
				257/E31.079;	
				257/E31.085	
TIO 4651015	 	Semiconductor imaging	250/208.1	257/258;	Nishizawa;
US 4651015	19870317	1 Schilleonductor imaging			1
US 4651015 A	19870317	1 -		257/261;	Junichi et al.
OS 4651015 A	19870317	device utilizing static		1	Junichi et al.
_	19870317	1 -		257/261; 257/264; 257/296;	Junichi et al.

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US 4644386 A	19870217 19870203	Integrated circuit employing insulated gate electrostatic induction transistor Semiconductor optoelectro	257/339 257/257	257/400; 257/E27.061; 257/E27.062; 257/E27.086; 257/E29.155; 257/E29.156; 257/E29.243 257/E29.243	Nishizawa; Junichi et al. Nishizawa;
A	170,0203	transducer		257/439; 257/E27.148; 257/E29.126; 257/E29.196; 257/E29.243; 257/E31.077; 257/E31.079	Jun-chi
US 4631592 A	19861223	Semiconductor image sensor	348/307	257/113; 257/136; 257/E27.148	Nishizawa; Jun-ichi
US 4629901 A	19861216	Photo coupler with static induction transistor type detector	250/551	257/136; 257/E31.079; 257/E31.095; 257/E31.108; 257/E31.109	Nishizawa; Jun-ichi
US 4626916 A	19861202	Solid state image pickup device	348/307	257/225; 257/258; 257/263; 257/E27.148; 348/296	Mizoguchi; Toyokazu et al.
US 4623909 A	19861118	Semiconductor photodetector	257/446	257/113; 257/435; 257/513; 257/E27.148; 257/E31.079	Nishizawa; Jun-ichi et al.
US 4619811 A	19861028	Apparatus for growing GaAs single crystal by using floating zone	117/202	117/222; 117/954; 373/139; 373/148	Nishizawa; Jun-ichi
US 4619718 A	19861028	Method of manufacturing a Group II-VI semiconductor device having a PN junction	438/501	117/56; 117/906; 117/956; 117/958; 257/E21.464; 257/E21.465; 257/E21.467;	Nishizawa; Jun-ichi

				257/E33.019; 438/22; 438/918	
US 4616249 A	19861007	Solid state image pick-up element of static induction transistor type	257/446	257/113; 257/E27.148	Nishizawa; Jun-ichi et al.
US 4613881 A	19860923	Vertical semiconductor photoelectric transducer with improved separated gate structure	257/257	257/263; 257/270; 257/E29.059; 257/E29.243; 257/E31.079	Nishizawa; Jun-ichi
US 4608587 A	19860826	Semiconductor optoelectro transducer	257/258	257/136; 257/432; 257/466; 257/E27.148; 257/E29.126; 257/E29.243; 257/E31.077	Nishizawa; Jun-ichi
US 4608582 A	19860826	Semiconductor device having non-saturating I-V characteristics and integrated circuit structure including same	257/497	257/264; 257/378; 257/512; 257/521; 257/E21.546; 257/E21.549; 257/E21.572; 257/E27.031; 257/E27.032; 257/E29.194	Nishizawa; Jun-ichi
US 4603420 A	19860729	Optical integrated circuit	372/45.01	372/46.01; 372/50.1	Nishizawa; Junichi et al.
US 4596605 A	19860624	Fabrication process of static induction transistor and solid-state image sensor device	438/57	257/264; 257/266; 257/285; 257/E21.335; 257/E21.401; 257/E29.086; 257/E29.243; 257/E31.079; 438/186; 438/528; 438/87	Nishizawa; Junichi et al.
US 4593320 A	19860603	Two-dimensional solid-state image pickup device	348/307	257/258; 257/263; 348/216.1	Nishizawa; Jun-ichi et al.
US 4589003	19860513	Solid state image sensor	257/258	257/262;	Yamada;

A		comprising photoelectric converting film and reading- out transistor		257/293; 257/E27.141; 257/E27.148	Hidetoshi et al.
US 4587562 A	19860506	Solid state image pick-up device	348/307	257/258; 257/263; 257/E27.148	Imai; Masaharu et al.
US 4574310 A	19860304	One-dimensional semiconductor imaging device	348/307	257/114; 257/136; 257/E27.148	Nishizawa; Jun-ichi et al.
US 4572763 A	19860225	Method and apparatus for performing epitaxial growth of ZnSe crystal from a melt thereof	117/59	117/64; 117/900; 117/906	Nishizawa; Jun-ichi
US 4571727 A	19860218	Far-infrared electromagnetic wave generator	372/4	372/50.11	Nishizawa; Jun-ichi et al.
US 4571624 A	19860218	Two-dimensional solid-state image sensor device	348/307	257/258; 257/263; 257/514	Nishizawa; Junichi et al.
US 4565156 A	19860121	Apparatus for performing solution growth relying on temperature difference technique	118/412	117/57; 117/61; 118/415; 118/425; 257/E21.114	Nishizawa; Jun-ichi et al.
US 4562474 A	19851231	Semiconductor image sensor	348/307	257/291; 257/E27.148	Nishizawa; Jun-ichi
US 4558660 A	19851217	Semiconductor fabricating apparatus	118/725	118/50.1; 219/411; 257/E21.349	Nishizawa; Jun-ichi et al.
US 4540466 A	19850910	Method of fabricating semiconductor device by dry process utilizing photochemical reaction, and apparatus therefor	438/708	118/50.1; 118/620; 118/728; 156/345.5; 204/192.25; 204/298.31; 204/298.33; 257/E21.101; 257/E21.214; 257/E21.252; 257/E21.279; 257/E21.347; 257/E21.349; 427/527; 427/586; 427/596; 438/758;	Nishizawa; Jun-ichi

				438/778	
US 4536946	19850827	Method for fabricating semiconductor	438/57	257/E27.131; 257/E27.148;	Nishizawa; Junichi et al.
A		photodetector		257/E29.059;	Jumem et ai.
		photodetector		438/193;	
				438/73	
US 4534033	19850806	Three terminal	372/50.1	257/136;	Nishizawa;
A		semiconductor laser		372/46.01	Jun-ichi et al.
US 4531156	19850723	Solid state image pickup	348/307	257/258;	Nishizawa;
Α		device		257/E27.148;	Jun-ichi et al.
				348/296	
US 4526632	19850702	Method of fabricating a	438/501	252/62.3ZT;	Nishizawa;
A		semiconductor pn junction		257/614;	Jun-ichi et al.
				257/78;	
				257/E21.464;	
				257/E21.465;	
				257/E21.467;	
				257/E21.468;	
				257/E21.47;	
				257/E29.098; 438/22;	
				438/502	
TIC 4505740	19850625	Two-dimensional solid-state	348/307	257/258;	Nishizawa;
US 4525742	19830023	image sensor device	346/307	257/263;	Junichi et al.
A		image sensor device		257/E27.148;	Juniom Ct un.
				257/E31.079	
US 4524391	19850618	Two-dimensional solid-state	348/307	257/258;	Nishizawa;
A		image sensor device		257/263;	Junichi et al.
				257/E27.148	
US 4506281	19850319	GaAs semiconductor device	257/264	257/273;	Nishizawa;
A				257/E21.268;	Jun-ichi et al.
				257/E21.697;	
				257/E29.194	271.1
US 4504865	19850312	Image signal readout methd	348/281	257/292;	Nishizawa;
A		for solid-state image sensor	0.55/0.64	257/443	Jun-ichi et al.
US 4504847	19850312	Static induction type	257/264	257/136;	Nishizawa; Jun-ichi
A		semiconductor device		257/266;	Jun-ichi
				257/285; 257/E29.049;	
				257/E29.049, 257/E29.196;	
				257/E29.190, 257/E29.243	
US 4502203	19850305	Method for fabricating	438/57	257/258;	Nishizawa;
A	17030303	semiconductor	1.50.57	257/443;	Junichi et al.
Λ λ		photodetector		257/E27.131;	
		Protogetor		257/E27.148;	
				438/195;	

 				438/98	
US 4499654 A	19850219	Method for fabricating semiconductor	438/57	257/113; 257/443;	Nishizawa; Junichi et al.
		photodetector		257/E27.131; 257/E27.148; 438/195;	
				438/196; 438/98	
US 4484207	19841120	Static induction transistor	257/192	257/183;	Nishizawa;
A	17011120	and semiconductor	2011132	257/200;	Jun-ichi et al.
• •		integrated circuit using		257/264;	
		hetero-junction		257/51;	
				257/E29.091;	
				257/E29.14;	
				257/E29.194	
US 4482910	19841113	Heterojunction emitter	257/26	257/198;	Nishizawa;
A		transistor with saturation		257/592;	Jun-ichi et al.
		drift velocity gradient in		257/E29.085;	
		base		257/E29.241	27: 1:
US 4475131	19841002	Image storage device	386/117	257/E27.128;	Nishizawa;
A				348/211.99;	Jun-ichi et al.
	10010010		240/200	358/906	Ni-hi-a
US 4472638	19840918	Two-dimensional solid-state	348/309	250/208.1;	Nishizawa; Jun-ichi et al.
Α		image sensor		257/E27.148; 348/308	Jun-ichi et ai.
US 4471228	19840911	Solid-state image sensor	348/298	250/208.1;	Nishizawa;
OS 44/1228	19840911	with exposure controller	346/296	257/E27.148;	Jun-ichi et al.
A		with exposure controller		348/362;	
				356/222;	
				356/406	
US 4470059	19840904	Gallium arsenide static	257/264	257/266;	Nishizawa;
A		induction transistor		257/279;	Jun-ichi et al.
				257/E29.021;	
				257/E29.059;	
				257/E29.089;	
				257/E29.194;	
				257/E29.243	
US 4465527	19840814	Method for producing a	117/79	117/61;	Nishizawa;
Α		group IIB-VIB compound		117/83;	Jun-ichi
		semiconductor crystal		117/939;	
				117/956;	
TIO 4454505	10040610	G	257/292	117/958 257/184;	Nishizawa;
US 4454526	19840612	Semiconductor image sensor	2311292	257/258;	Jun-ichi et al.
A		and the method of operating		257/E27.148	Jun-iom et ai.
110 4450460	10040522	the same	257/264	257/E27.148 257/497;	Nishizawa;
US 4450468	19840522	Gallium arsenide ISL gate	2311204	2311 4 71,	141511124444,

A		with punched-through		257/575;	Junichi et al.
		bipolar driver transistor		326/109;	
		•		326/114	
US 4450466	19840522	Semiconductor image sensor	257/292	257/E21.557;	Nishizawa;
A		, and the second		257/E27.148;	Jun-ichi et al.
				257/E31.07	
US 4436770	19840313	Oxynitride film and its	427/570	204/192.15;	Nishizawa;
A		manufacturing method		257/E21.269;	Jun-ichi et al.
				257/E29.162;	
				257/E29.345;	
				427/162;	
				427/255.29;	
				427/255.34;	
				427/255.394;	
				427/96.8;	
				438/779;	
				438/784	
US 4434433	19840228	Enhancement mode JFET	257/264	257/298;	Nishizawa;
A	İ	dynamic memory		257/306;	Jun-ichi
				257/316;	
				257/E27.075;	
				257/E29.243;	
				365/149;	
				365/185.01	
US 4427990	19840124	Semiconductor photo-	257/258	257/260;	Nishizawa;
A		electric converter with	!	257/264;	Jun-ichi
		insulated gate over p-n		257/E27.148;	
		charge storage region		257/E31.079	
US 4425143	19840110	Adsorption by zeolitic	95/126	422/169;	Nishizawa;
Α		composition		423/219;	Junichi et al.
			i	423/351;	
				95/138;	
				96/146	
US 4416952	19831122	Oxynitride film and its	428/698	148/33.3;	Nishizawa;
A		manufacturing method		204/192.26;	Jun-ichi et al.
				257/411;	
				257/E21.269;	
				257/E29.162;	
				257/E29.345;	
				423/353;	
				423/392;	
				428/469;	
				428/697;	
				428/701;	
				428/702	
US 4415937	19831115	Solid-state image storage	386/117	257/E27.148;	Nishizawa;

A		device		358/906	Jun-ichi et al.
US 4414558	19831108	Hetero-junction light-	257/96	257/E33.043;	Nishizawa;
Α		emitting diode		257/E33.049;	Jun-ichi et al.
				372/50.1	
US 4408304	19831004	Semiconductor memory	365/174	257/306;	Nishizawa;
Α				257/378;	Jun-ichi et al.
				257/E27.084;	
				365/243	
US 4404575	19830913	Semiconductor device	257/264	257/247;	Nishizawa;
Α				257/E29.021;	Jun-ichi
				257/E29.165;	
				257/E29.194;	
				257/E29.243	
US 4400710	19830823	Semiconductor device	257/136	12/22; 12/38;	Nishizawa;
A				257/155;	Jun-ichi et al.
				257/264;	
				257/474;	
				257/E29.194;	
				257/E29.196;	
				257/E29.271;	
				257/E29.31;	
				257/E29.311	
US 4389256	19830621	Method of manufacturing pn	438/45	117/2;	Nishizawa;
A		junction in group II-VI		257/E21.467;	Jun-ichi et al.
		compound semiconductor		257/E21.468;	!
			,	257/E21.47;	
			:	257/E29.098;	
			1	438/501;	
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				438/796;	
				438/971	
US 4377817	19830322	Semiconductor image	257/258	257/264;	Nishizawa;
Α		sensors		257/447;	Jun-ichi et al.
				257/E27.148;	
				257/E31.079	
US 4371412	19830201	Dry etching apparatus	156/345.45	118/723I;	Nishizawa;
Α				204/298.34;	Junichi
				204/298.39;	
				216/67;	
				216/71	N: 1:
US 4365262	19821221	Semiconductor image sensor	257/258	257/E27.148	Nishizawa;
Α			0.77/25:	0.57/10.6	Junichi
US 4364072	19821214	Static induction type	257/264	257/136;	Nishizawa;
Α		semiconductor device with		257/266;	Jun-ichi
		multiple doped layers for		257/285;	
		potential modification		257/E29.049;	

				257/E29.196; 257/E29.243	
US 4359012 A	19821116	Apparatus for producing a semiconductor device utlizing successive liquid growth	118/59	118/412; 118/415	Nishizawa; Jun-ichi
US 4354140 A	19821012	Light-emitting semiconductor	313/499	257/185; 257/E33.045; 257/E33.049	Nishizawa; Jun-ichi
US 4347097 A	19820831	Method and apparatus for producing a multilayer semiconductor device utilizing liquid growth	117/57	117/67; 117/954; 118/412; 422/253	Nishizawa; Jun-ichi
US 4346513 A	19820831	Method of fabricating semiconductor integrated circuit device utilizing selective etching and epitaxial refill	438/187	117/902; 257/515; 257/521; 257/E21.09; 257/E21.123; 257/E21.223; 257/E21.231; 257/E21.54; 257/E21.56; 438/192; 438/357; 438/401; 438/418; 438/975	Nishizawa; Junichi et al.
US 4340827 A	19820720	Semiconductor integrated circuit	326/100	257/273; 257/575; 326/109	Nishizawa; Jun-ichi et al.
US 4338618 A	19820706	Composite static induction transistor and integrated circuit utilizing same	257/264	257/273; 257/E27.032; 257/E27.069; 257/E29.194	Nishizawa; Jun-ichi
US 4337473 A	19820629	Junction field effect transistor having unsaturated drain current characteristic with lightly doped drain region	257/264	257/266; 257/E29.059; 257/E29.243	Nishizawa; Jun-ichi
US 4334235 A	19820608	Insulated gate type semiconductor device	257/344	257/331; 257/345; 257/E29.04; 257/E29.051; 257/E29.133; 257/E29.243	Nishizawa; Jun-ichi Nishizawa;
US 4333989	19820608	Sapphire single crystal	428/446	LJ LL 1.1 L 1,	1 TISHIZAWA,

A	1	substrate consisting		428/700;	Jun-Ichi et al.
2 1		essentially of Ga.sub.2		501/153;	
		O.sub. 3		501/86	
US 4331737	19820525	Oxynitride film and its	428/457	148/33.3;	Nishizawa;
A	17020323	manufacturing method	120, 15.	257/435;	Jun-ichi et al.
Λ		manaractaring metrica		257/E21.269;	
	ļ			257/E29.162;	
				257/E29.345;	
				428/689;	
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				428/698;	
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				438/958	
US 4329625	19820511	Light-responsive light-	315/158	257/257;	Nishizawa;
	19620311	emitting diode display	313/136	257/261;	Jun-ichi et al.
Α		emitting diode display		257/264;	Jun-10111 of an
				257/266;	
				257/82;	
				257/82, 257/E31.079;	
				257/E31.079; 257/E33.076;	
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				315/192;	
				315/311;	
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				315/53;	
				327/109;	
				327/514;	
				362/800	
US 4326209	19820420	Static induction transistor	257/264	257/268;	Nishizawa;
	19620420	Static induction transistor	2511204	257/284;	Jun-ichi et al.
A		·		257/E29.243	Jun 10111 of un.
110 4220410	19820316	GaAs Semiconductor device	257/264	257/273;	Nishizawa;
US 4320410	19620310	GaAs Semiconductor device	2511204	257/E21.268;	Jun-ichi et al.
A				257/E21.208, 257/E21.697;	Juli-leni et al.
				257/E21.077, 257/E29.194	
110 4217127	19820223	Static induction transistor	257/264	148/DIG.85;	Nishizawa;
US 4317127	19820223		2377204	148/DIG.87;	Jun-ichi
A		and integrated circuit		257/273;	Juli-loin
		utilizing same		257/289;	
				257/471;	
				257/E29.194;	
				326/100;	
				326/131	
110 421 570 6	10020216	Country of a framework	117/57	117/61;	Nishizawa;
US 4315796	19820216	Crystal growth of compound	117/57	117/61;	Jun-ichi
<u>A</u>		semiconductor mixed	<u> </u>	11//04,	Jun-icin

	1		ι	117/67	
		crystals under controlled		117/67;	
		vapor pressure		117/906;	
				117/912;	
				117/953;	
				117/954;	
				117/955;	
				117/956;	
				148/DIG.6	
TTG 4000151	10011110	C1	257/217		Nichigarya
US 4300151	19811110	Change transfer device with	257/217	257/216;	Nishizawa;
A		PN Junction gates		257/E29.228;	Jun-ichi
				377/58;	
				377/62	
US 4297718	19811027	Vertical type field effect	257/259	257/266;	Nishizawa;
A		transistor		257/E29.313	Jun-Ichi et al.
US 4296425	19811020	Luminescent diode having	257/96	257/773;	Nishizawa;
A	17011020	multiple hetero junctions	23,770	257/E21.117;	Jun-ichi
A				438/47	Juli lom
TTG 1000071	10010000		420/446		Nichigarra
US 4292374	19810929	Sapphire single crystal	428/446	117/902;	Nishizawa;
A		substrate for semiconductor		148/33;	Jun-ichi et al.
		devices	:	148/DIG.150;	
				148/DIG.72;	
	•		_	148/DIG.79;	
	-			148/DIG.97;	
				257/E21.121;	
				428/697;	·
				428/700;	
				501/86	
110 4000070	10010000	C 1:	428/446		Nishizawa;
US 4292373	19810929	Sapphire single crystal	428/446	117/902;	Jun-ichi et al.
A		substrate for semiconductor		148/33;	Jun-ichi et ai.
		devices		148/DIG.150;	
				148/DIG.72;	
				148/DIG.97;	
				257/E21.121;	
			ľ	428/697;	
				428/700;	
				501/86	
US 4284997	19810818	Static induction transistor	257/264	257/262;	Nishizawa;
	12010010	1	2377207	257/270;	Jun-ichi
A		and its applied devices		1	Juli-ioni
				257/273;	
				257/386;	
	1			257/498;	
				257/E29.194;	
				257/E29.243;	
				326/100;	
				326/101	
US 4271408	19810602	Colored-light emitting	345/83	340/815.45;	Teshima; Toru
<u> </u>	1701002	1			·

Α		display		340/815.56;	et al.
A		display		340/815.75;	ot ai.
				345/697;	
				362/240;	
				362/293;	
				362/800;	
				362/812;	
				40/564;	
				40/581	
	10010506		226/100		Nichicarra
-	19810526	Static induction transistor	326/100	257/264;	Nishizawa; Jun-ichi et al.
Α		logic circuit		257/273;	Jun-ichi et ai.
				257/E27.032;	
				257/E27.069;	
				257/E29.194;	
				326/109	
US 4266238	19810505	Semiconductor device	257/544	257/264;	Nishizawa;
A		having high-speed operation		257/335;	Jun-ichi
		and integrated circuit using		257/386;	
		same		257/552;	
				257/E27.031;	
				257/E29.034;	
				257/E29.062;	:
		•		257/E29.063;	
				257/E29.243;	
				326/101	
US 4259681	19810331	Integrated circuit	257/264	148/DIG.168;	Nishizawa;
A				148/DIG.50;	Jun-ichi
				148/DIG.51;	
				257/273;	
				257/E21.608;	
				257/E27.032;	
				257/E27.069;	
				257/E29.194;	
				326/100;	٠
				326/101;	
				326/17	
US 4233109	19801111	Dry etching method	216/67	118/723I;	Nishizawa;
A				204/164;	Junichi
				204/192.34;	
				204/298.39;	
				422/186.05;	
				438/711;	
				438/712;	
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				438/730; 438/732	

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A		manufacturing process thereof		257/273; 257/285; 257/E21.033; 257/E29.194; 438/192; 438/193; 438/545; 438/552; 438/942	Jun-ichi et al.
US 4199771 A	19800422	Static induction transistor	257/264	257/266; 257/E29.243; 438/192; 438/193	Nishizawa; Jun-Ichi et al.
US 4198648 A	19800415	Integrated semiconductor device	257/264	257/273; 257/E27.032; 257/E27.069; 257/E29.194; 326/100	Nishizawa; Jun-ichi
US 4198645 A	19800415	Semiconductor controlled rectifier having gate grid dividing surrounding zone into two different impurity concentration sections	257/136	257/155; 257/264; 257/266; 257/270; 257/E29.196	Nishizawa; Jun-ichi
US 4177321 A	19791204	Single crystal of semiconductive material on crystal of insulating material	428/446	117/101; 156/78; 257/E21.121; 428/428; 428/432; 428/700; 438/967	Nishizawa; Jun-ichi
US 4171995 A	19791023	Epitaxial deposition process for producing an electrostatic induction type thyristor	438/137	148/DIG.88; 257/136; 257/E21.362; 257/E29.196; 438/499; 438/505	Nishizawa; Jun-ichi et al.
US 4160259 A	19790703	Semiconductor device	257/264	257/268; 257/270; 257/E29.022; 257/E29.059; 257/E29.243; 257/E29.264; 257/E29.312; 257/E29.313; 257/E29.319;	Nishizawa; Jun-ichi

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US RE29971 E	19790417	Field effect semiconductor device having an unsaturated triode vacuum tube characteristic	257/264	257/403; 257/E29.243	Nishizawa; Jun-ichi et al.
US 4126731 A	19781121	Sapphire single crystal substrate for semiconductor devices	428/446	117/902; 257/E21.121; 423/600; 428/700; 501/153; 501/86	Nishizawa; Jun-ichi et al.
US 4115793 A	19780919	Field effect transistor with reduced series resistance	257/266	148/DIG.88; 257/286; 257/E29.039; 257/E29.059; 438/173; 438/193	Nishizawa; Jun-ichi
US 4086611 A	19780425	Static induction type thyristor	257/136	148/DIG.88; 257/145; 257/E29.196	Nishizawa; Jun-ichi et al.
US 4038610 A	19770726	Luminosity control system employing semiconductor lasers	372/8	359/336; 359/344; 372/46.01; 372/50.1	Nishizawa; Jun-ichi et al.
US 3990902 A	19761109	Magnesium-titanate- comprising spinel single crystal substrate for semiconductor devices	501/134	257/E21.121; 501/153	Nishizawa; Jun-ichi et al.
US 3986060 A	19761012	Compound transistor circuitry	327/581	330/207P; 330/277; 330/298; 361/58; 361/98	Nishizawa; Jun-ichi et al.
US 3947548 A	19760330	Process of growing single crystals of gallium phosphide	117/3	117/67; 117/79; 117/955; 423/305	Nishizawa; Jun-Ichi et al.
US 3946270 A	19760323	Signal collecting and distributing systems	348/800	257/E27.133	Nishizawa; Jun-ichi et al.
US 3896484 A	19750722	Intrinsic semiconductor charge transfer device using alternate transfer of electrons and holes	257/215	257/218; 257/912; 257/E29.058; 257/E29.065; 257/E29.239; 327/581	Nishizawa; Jun-ichi et al.
US 3889164	19750610	Position control system	318/640	318/577;	Nishizawa;

·				210/504	Trans 1.1 . 4 . 1
A		using magnetic forces for		318/594;	Junichi et al.
		correcting the inclination of		318/603;	
		a controlled member		318/687;	
		including a torsional		356/500;	
		mounting		356/510	> 71 1 1
US 3883862	19750513	Signal collecting and	345/80	250/553	Nishizawa;
Α		distributing systems		_	Jun-Ichi et al.
US 3880677	19750429	Method for producing a	117/3	117/79;	Nishizawa;
A		single crystal of In.sub.x		117/955;	Jun-Ichi et al.
		Ga.sub.1.subx P		252/62.3GA;	
		33333		420/555	
US 3871764	19750318	Pattern generator apparatus	355/18	355/40;	Nishizawa;
A				396/548	Junichi
US 3836999	19740917	SEMICONDUCTOR WITH	148/33	148/DIG.40;	Nishizawa;
A		GROWN LAYER		148/DIG.67;	Jun-Ichi
		RELIEVED IN LATTICE		148/DIG.72;	
		STRAIN		148/DIG.97;	
				257/607;	
				257/655;	
				257/E21.102;	
				257/E29.086;	
				438/938	
US 3829885	19740813	CHARGE COUPLED	257/215	257/227;	Nishizawa;
A	157 10015	SEMICONDUCTOR		257/E29.058;	Junichi et al.
7 L	1	MEMORY DEVICE		257/E29.239;	
		WIEWORT BEVICE		327/581	
US 3828230	19740806	FIELD EFFECT	257/264	148/DIG.145;	Nishizawa;
A	17740000	SEMICONDUCTOR	2377201	148/DIG.53;	Jun-Ichi et al.
А		DEVICE HAVING AN		257/327;	
		UNSATURATED TRIODE		257/365;	
		VACUUM TUBE		257/E29.243	
		CHARACTERISTI		2011221213	
US 3809953	19740507	METHOD OF AND	359/321	257/E27.129;	Nishizawa;
A	19740307	DEVICE FOR	337/321	257/E31.114	Jun-Ichi
А		CONTROLLING		20112511111	
	,	OPTICAL CONVERSION			
		IN SEMICONDUCTOR			
US 3793093	19740219	METHOD FOR	438/546	148/DIG.18;	Nishizawa;
OS 3793093 A	19/70219	PRODUCING A	133/3/10	148/DIG.40;	Junichi et al.
Λ		SEMICONDUCTOR		148/DIG.56;	
		DEVICE HAVING A		148/DIG.61;	
		VERY SMALL		148/DIG.65;	
		DEVIATION IN LATTICE		148/DIG.97;	
		CONSTANT		252/62.3GA;	
		CONSTAINT		257/E29.086;	
				257/E29.093;	
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US 3789317 A	19740129	SIGNAL CONVERTER WHEREIN PHOTOEMISSION TIME CONSTANT IS UTILIZED	372/8	257/461; 257/80; 359/336	Nishizawa; Junichi
US 3789285 A	19740129	POSITION CONTROL SYSTEM USING MAGNETIC FORCE	318/687	310/12; 318/594; 318/640; 318/676; 335/268	Nishizawa; Junichi
US 3762367 A	19731002	GROWTH APPARATUS FOR A LIQUID GROWTH MULTI-LAYER FILM	118/422	117/57; 118/423; 257/E21.117	Nishizawa; Junichi et al.
US 3760201 A	19730918	OPTICAL FLIP-FLOP ELEMENT	372/8	327/187; 372/49.01	Nishizawa; Jun-ichi et al.
US 3634849 A	19720111	SIGNAL COLLECTING AND DISTRIBUTING SYSTEMS	250/214R	257/E27.133; 333/217	Nishizawa; Jun-Ichi et al.
US 3633059 A	19720104	ELECTROLUMINESCENT PN JUNCTION SEMICONDUCTOR DEVICE FOR USE AT HIGHER FREQUENCIES	313/499	257/101; 257/610	Nishizawa; Jun-ichi et al.
US 3614197 A	19711019	SOLID OPTICAL WAVE GUIDE HAVING A RADIALLY VARYING REFRACTIVE INDEX	385/124	250/227.28; 65/30.1; 65/37; 65/60.8	Nishizawa; Jun-ichi et al.
US 3602840 A	19710831	TRANSIT TIME DIODE OSCILLATOR USING TUNNEL INJECTION	331/96	257/604; 257/656; 257/657; 331/107DP; 331/107R; 331/107T	Nishizawa; Jun-ichi et al.
US 3538352 A	19701103	VARIABLE IMPEDANCE ACTIVE PULSE TRANSMISSION SYSTEM [TEXT AVAILABLE IN USOCR DATABASE]	327/177	327/195; 327/514	NISHIZAWA JUN-ICHI
US 3493823 A	19700203	NEGATIVE-RESISTANCE SEMICONDUCTOR DEVICE FOR HIGH FREQUENCIES [TEXT AVAILABLE IN USOCR	257/480	257/482; 257/595; 257/604	NISHIZAWA JUNICHI et al.

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